



# CYPRESS

CY7C168A

4Kx4 RAM

## Features

- Automatic power-down when deselected
  - CMOS for optimum speed/power
  - High speed
    - $t_{AA} = 15 \text{ ns}$
  - Low active power
    - 633 mW
  - Low standby power
    - 110 mW
  - TTL-compatible inputs and outputs
  - $V_{IH}$  of 2.2V
  - Capable of withstanding greater than 2001V electrostatic discharge

## Functional Description

The CY7C168A is a high-performance CMOS static RAM organized as 4096 by 4 bits. Easy memory expansion is provided by an active LOW Chip Enable ( $\overline{CE}$ ) and three-state drivers. The CY7C168A has an automatic power-down feature, reducing the power consumption by 77% when deselected.

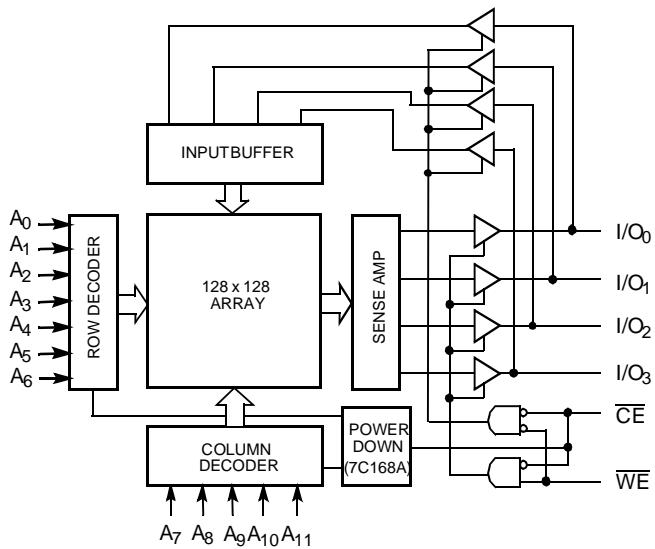
Writing to the device is accomplished when the Chip Select ( $\overline{CE}$ ) and Write Enable ( $\overline{WE}$ ) inputs are both LOW. Data on the four data input/output pins ( $I/O_0$  through  $I/O_3$ ) is written into the memory location specified on the address pins ( $A_0$  through  $A_{11}$ ).

Reading the device is accomplished by taking the Chip Enable ( $\overline{CE}$ ) LOW, while Write Enable ( $\overline{WE}$ ) remains HIGH. Under these conditions, the contents of the location specified on the address pins will appear on the four data input/output pins ( $I/O_0$  through  $I/O_3$ ).

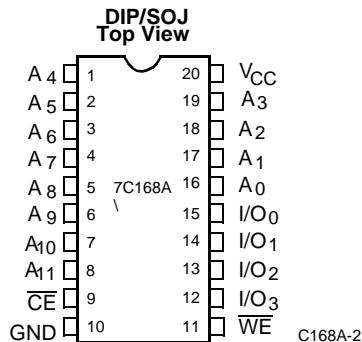
The input/output pins remain in a high-impedance state when Chip Enable ( $\overline{CE}$ ) is HIGH or Write Enable ( $\overline{WE}$ ) is LOW.

A die coat is used to insure alpha immunity.

# Logic Block Diagram



## Pin Configurations



## Selection Guide

		7C168A-15	7C168A-20	7C168A-25	7C168A-35	7C168A-45
Maximum Access Time (ns)		15	20	25	35	45
Maximum Operating Current (mA)	Commercial	115	90	90	90	90
	Military	-	100	100	100	100

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... $-65^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$

Ambient Temperature with

Power Applied ..... $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$

Supply Voltage to Ground Potential

(Pin 20 to Pin 10) ..... $-0.5\text{V}$  to  $+7.0\text{V}$

DC Voltage Applied to Outputs

in High Z State ..... $-0.5\text{V}$  to  $+7.0\text{V}$

DC Input Voltage ..... $-3.0\text{V}$  to  $+7.0\text{V}$

Output Current into Outputs (Low) ..... $20\text{ mA}$

Static Discharge Voltage ..... $>2001\text{V}$   
(per MIL-STD-883, Method 3015)

Latch-Up Current ..... $>200\text{ mA}$

## Operating Range

Range	Ambient Temperature	$V_{CC}$
Commercial	$0^{\circ}\text{C}$ to $+70^{\circ}\text{C}$	$5\text{V} \pm 10\%$
Military <sup>[1]</sup>	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$	$5\text{V} \pm 10\%$

## Electrical Characteristics

 Over the Operating Range<sup>[2]</sup>

Parameter	Description	Test Conditions	7C168A-15		7C168A-20		Unit
			Min.	Max.	Min.	Max.	
$V_{OH}$	Output HIGH Voltage	$V_{CC} = \text{Min.}$ , $I_{OH} = -4.0\text{ mA}$	2.4		2.4		V
$V_{OL}$	Output LOW Voltage	$V_{CC} = \text{Min.}$ , $I_{OL} = 8.0\text{ mA}$		0.4		0.4	V
$V_{IH}$	Input HIGH Voltage		2.2	$V_{CC}$	2.2	$V_{CC}$	V
$V_{IL}$	Input LOW Voltage <sup>[3]</sup>		-0.5	0.8	-0.5	0.8	V
$I_{IX}$	Input Load Current	$\text{GND} \leq V_I \leq V_{CC}$	-10	+10	-10	+10	$\mu\text{A}$
$I_{OZ}$	Output Leakage Current	$\text{GND} \leq V_O \leq V_{CC}$ , Output Disabled	-10	+10	-10	+10	$\mu\text{A}$
$I_{OS}$	Output Short Circuit Current <sup>[4]</sup>	$V_{CC} = \text{Max.}$ , $V_{OUT} = \text{GND}$		-350		-350	mA
$I_{CC}$	$V_{CC}$ Operating Supply Current	$V_{CC} = \text{Max.}$ , $I_{OUT} = 0\text{ mA}$	Com'l	115		90	mA
			Mil		-	100	
$I_{SB1}$	Automatic $\overline{CE}$ Power-Down Current	Max. $V_{CC}$ , $\overline{CE} \geq V_{IH}$	Com'l	40		40	mA
			Mil		-	40	
$I_{SB2}$	Automatic $\overline{CE}$ Power-Down Current	Max. $V_{CC}$ , $\overline{CE} \geq V_{CC} - 0.3\text{V}$	Com'l	20		20	mA
			Mil		-	20	

### Notes:

- $T_A$  is the "instant on" case temperature.
- See the last page of this specification for Group A subgroup testing information.
- $V_{IL}$  min. =  $-3.0\text{V}$  for pulse durations less than 30 ns.
- Not more than 1 output should be shorted at one time. Duration of the short circuit should not exceed 30 seconds.

**Electrical Characteristics** Over the Operating Range<sup>[2]</sup> (continued)

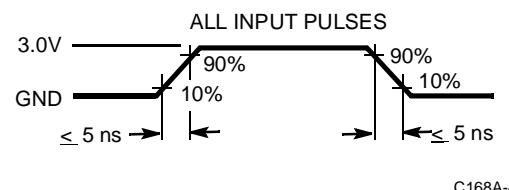
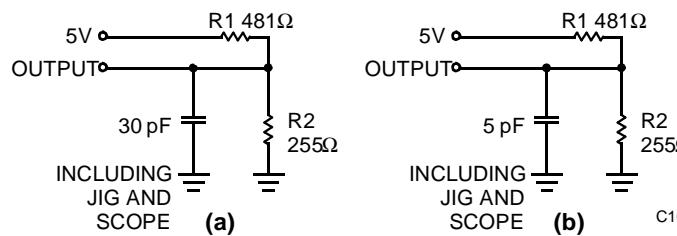
Parameter	Description	Test Conditions	7C168A-25		7C168A-35		7C168A-45		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA	2.4		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA		0.4		0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage		2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage <sup>[3]</sup>		-0.5	0.8	-0.5	0.8	-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	-10	+10	-10	10	-10	10	μA
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>O</sub> ≤ V <sub>CC</sub> Output Disabled	-10	+10	-50	50	-50	50	μA
I <sub>OS</sub>	Output Short Circuit Current <sup>[4]</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> = GND		-350		-350		-350	mA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA	Com'l		90		90		mA
			Mil		100		100		
I <sub>SB1</sub>	Automatic CE Power-Down Current	Max. V <sub>CC</sub> , CE ≥ V <sub>IH</sub>	Com'l		20		20		mA
			Mil		20		20		
I <sub>SB2</sub>	Automatic CE Power-Down Current	Max. V <sub>CC</sub> , CE ≥ V <sub>CC</sub> - 0.3 V	Com'l		20		20		mA
			Mil		20		20		

**Capacitance<sup>[5]</sup>**

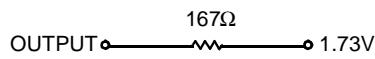
Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	T <sub>A</sub> = 25°C, f = 1 MHz, V <sub>CC</sub> = 5.0V	10	pF
C <sub>OUT</sub>	Output Capacitance		10	pF

**Note:**

5. Tested initially and after any design or process changes that may affect these parameters.

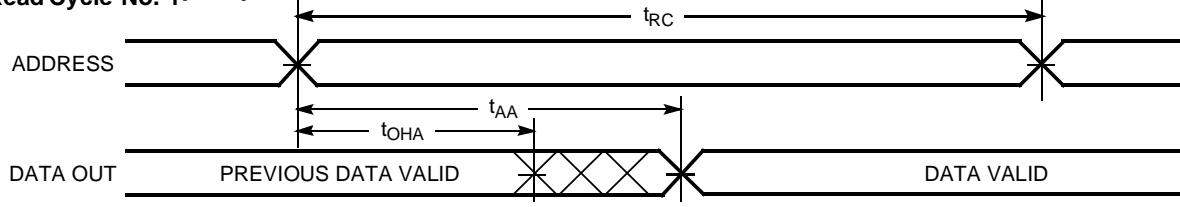
**AC Test Loads and Waveforms**


Equivalent to: THÉVENIN EQUIVALENT



**Switching Characteristics** Over the Operating Range<sup>[2,6]</sup>

Parameter	Description	7C168A-15		7C168A-20		7C168A-25		7C168A-35		7C168A-45		Unit
		Min.	Max.									
<b>READ CYCLE</b>												
t <sub>RC</sub>	Read Cycle Time	15		20		25		35		45		ns
t <sub>AA</sub>	Address to Data Valid		15		20		25		35		45	ns
t <sub>OHA</sub>	Output Hold from Address Change	5		5		5		5		5		ns
t <sub>ACE</sub>	Power Supply Current		15		20		25		35		45	ns
t <sub>LZCE</sub>	$\overline{CE}$ LOW to Low Z <sup>[7]</sup>	5		5		5		5		5		ns
t <sub>HZCE</sub>	$\overline{CE}$ HIGH to High Z <sup>[7, 8]</sup>		8		8		10		15		15	ns
t <sub>PU</sub>	$\overline{CE}$ LOW to Power Up	0		0		0		0		0		ns
t <sub>PD</sub>	$\overline{CE}$ HIGH to Power-Down		15		20		20		20		25	ns
t <sub>RCS</sub>	Read Command Set-Up	0		0		0		0		0		ns
t <sub>RCH</sub>	Read Command Hold	0		0		0		0		0		ns
<b>WRITE CYCLE<sup>[9]</sup></b>												
t <sub>WC</sub>	Write Cycle Time	15		20		20		25		40		ns
t <sub>SCE</sub>	$\overline{CE}$ LOW to Write End	12		15		20		25		30		ns
t <sub>AW</sub>	Address Set-Up to Write End	12		15		20		25		30		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		0		0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		0		0		0		ns
t <sub>PWE</sub>	$\overline{WE}$ Pulse Width	12		15		15		20		20		ns
t <sub>SD</sub>	Data Set-Up to Write End	10		10		10		15		15		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		0		0		0		ns
t <sub>LZWE</sub>	$\overline{WE}$ HIGH to Low Z <sup>[7]</sup>	7		7		7		5		5		ns
t <sub>HZWE</sub>	$\overline{WE}$ LOW to High Z <sup>[7, 8]</sup>	5		5		5		5		10		ns

**Switching Waveforms**
**Read Cycle No. 1**<sup>[10, 11]</sup>


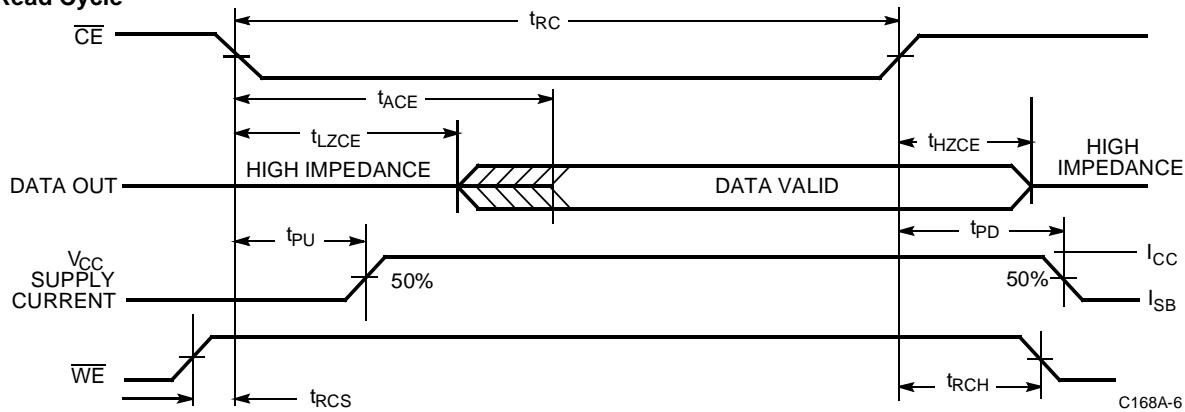
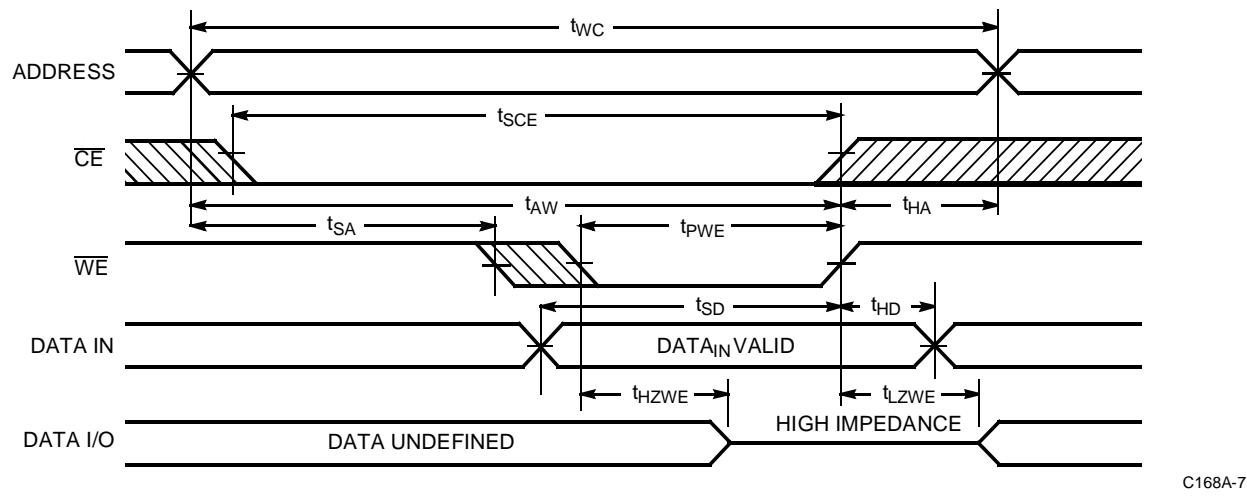
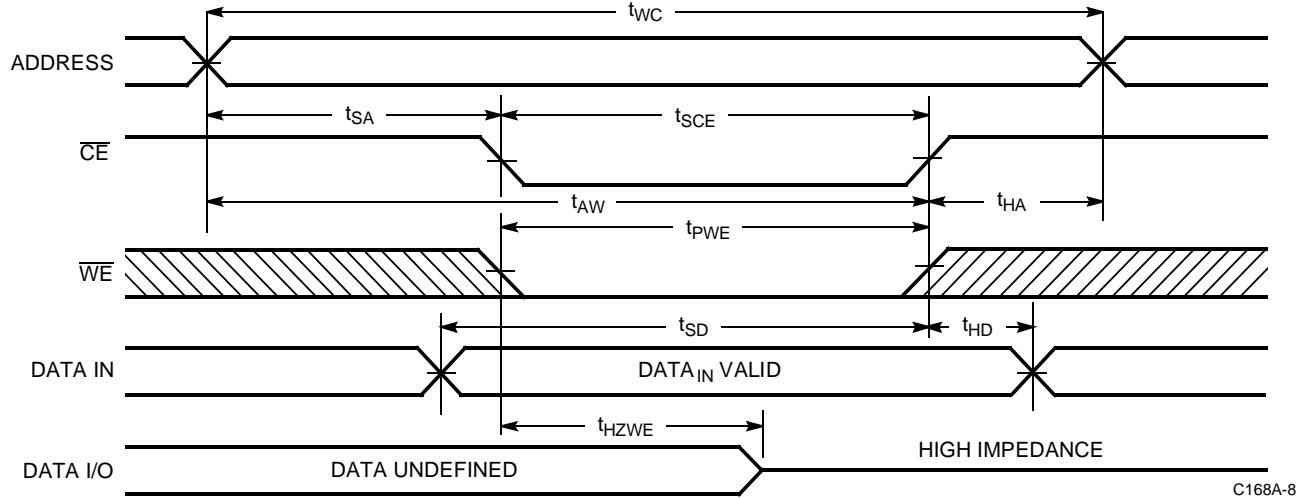
C168A-5

**Notes:**

6. Test conditions assume signal transition times of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified  $I_{OL}/I_{OH}$  and 30-pF load capacitance.
7. At any given temperature and voltage condition, t<sub>HZ</sub> is less than t<sub>LZ</sub> for all devices. Transition is measured  $\pm 500$  mV from steady state voltage with specified loading in part (b) of AC Test Loads and Waveforms.
8. t<sub>HZCE</sub> and t<sub>HZWE</sub> are tested with C<sub>L</sub> = 5 pF as in part (a) of Test Loads and Waveforms. Transition is measured  $\pm 500$  mV from steady state voltage.
9. The internal write time of the memory is defined by the overlap of  $\overline{CE}$  LOW and  $\overline{WE}$  LOW. Both signal must be LOW to initiate a write and either signal can terminate a write by going high. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
10.  $\overline{WE}$  is HIGH for read cycle.
11. Device is continuously selected,  $\overline{CE} = V_{IL}$ .



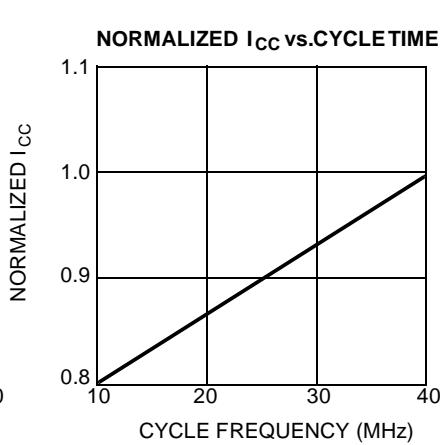
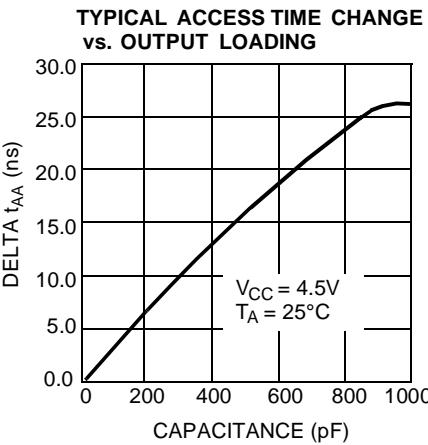
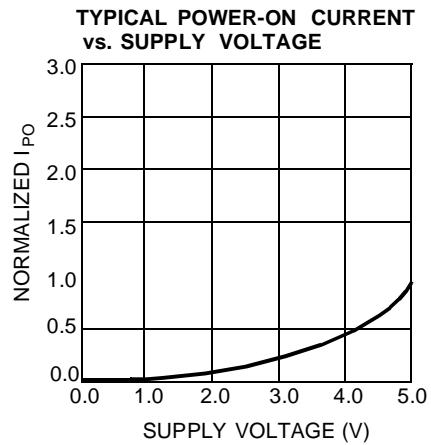
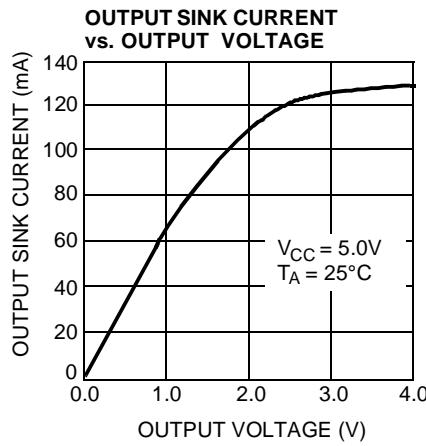
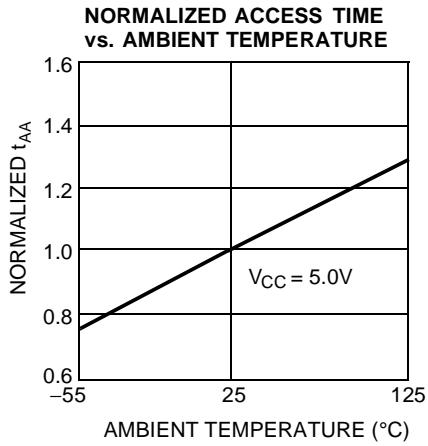
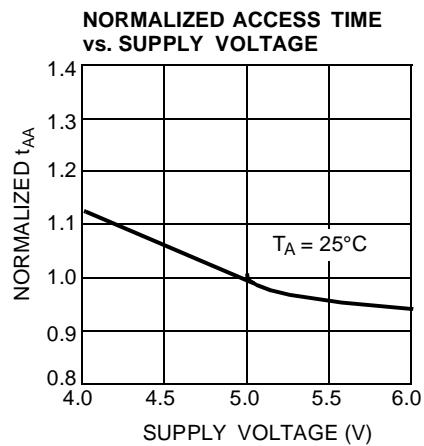
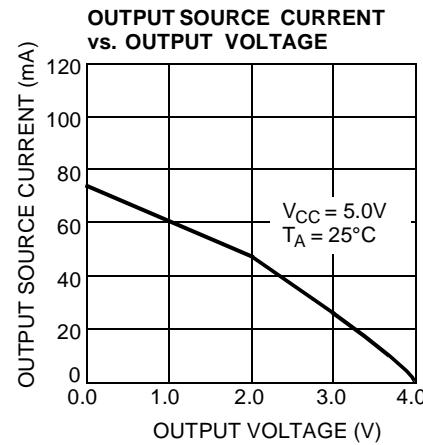
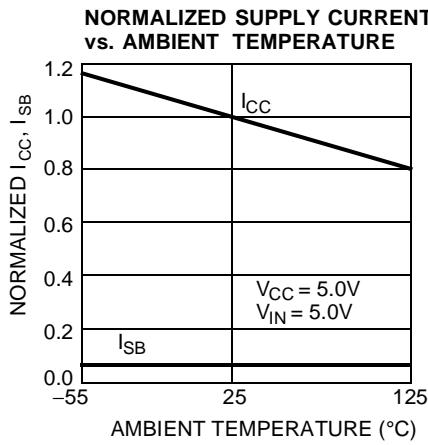
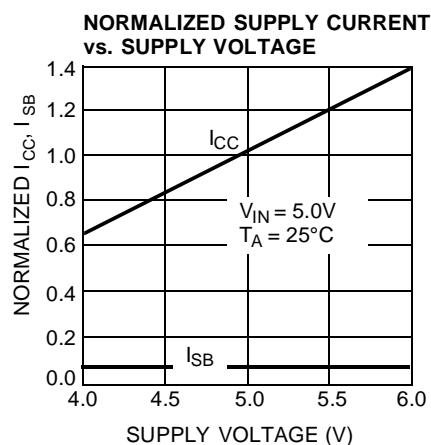
## Switching Waveforms (continued)

Read Cycle<sup>[10, 12]</sup>Write Cycle No. 1 ( $\overline{WE}$  Controlled)<sup>[9]</sup>Write Cycle No. 2 ( $\overline{CS}$  Controlled)<sup>[9, 13]</sup>

## Notes:

12. Address valid prior to or coincident with  $\overline{CE}$  transition LOW.
13. If  $CE$  goes HIGH simultaneously with  $WE$  HIGH, the output remains in a high-impedance state.

## Typical DC and AC Characteristics



### Ordering Information

<b>Speed (ns)</b>	<b>I<sub>CC</sub> (mA)</b>	<b>Ordering Code</b>	<b>Package Name</b>	<b>Package Type</b>	<b>Operating Range</b>
15	115	CY7C168A-15PC	P5	20-Lead (300-Mil) Molded DIP	Commercial
		CY7C168A-15VC	V5	20-Lead Molded SOJ	
20	90	CY7C168A-20PC	P5	20-Lead (300-Mil) Molded DIP	Commercial
		CY7C168A-20VC	V5	20-Lead Molded SOJ	
		CY7C168A-20DMB	D6	20-Lead (300-Mil) CerDIP	Military
25	70	CY7C168A-25PC	P5	20-Lead (300-Mil) Molded DIP	Commercial
		CY7C168A-25VC	V5	20-Lead Molded SOJ	
	80	CY7C168A-25DMB	D6	20-Lead (300-Mil) CerDIP	Military
35	70	CY7C168A-35PC	P5	20-Lead (300-Mil) Molded DIP	Commercial
		CY7C168A-35VC	V5	20-Lead Molded SOJ	
		CY7C168A-35DMB	D6	20-Lead (300-Mil) CerDIP	Military
45	70	CY7C168A-45PC	P5	20-Lead (300-Mil) Molded DIP	Commercial
		CY7C168A-45VC	V5	20-Lead Molded SOJ	
		CY7C168A-45DMB	D6	20-Lead (300-Mil) CerDIP	Military

### MILITARY SPECIFICATIONS Group A Subgroup Testing

#### DC Characteristics

Parameter	Subgroups
V <sub>OH</sub>	1, 2, 3
V <sub>OL</sub>	1, 2, 3
V <sub>IH</sub>	1, 2, 3
V <sub>IL</sub> Max.	1, 2, 3
I <sub>IX</sub>	1, 2, 3
I <sub>OZ</sub>	1, 2, 3
I <sub>CC</sub>	1, 2, 3
I <sub>SB1</sub>	1, 2, 3
I <sub>SB2</sub>	1, 2, 3

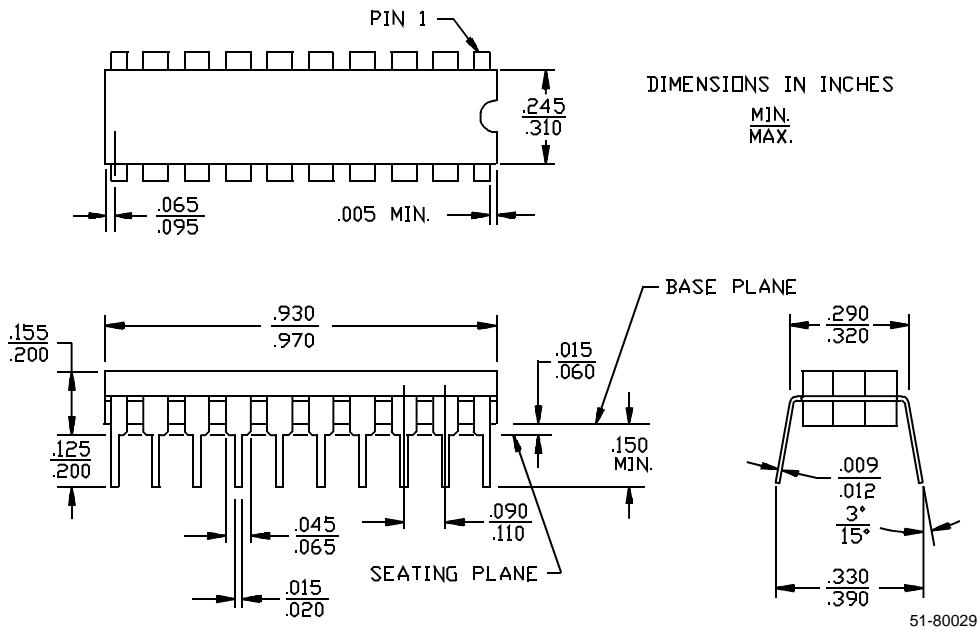
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#### Switching Characteristics

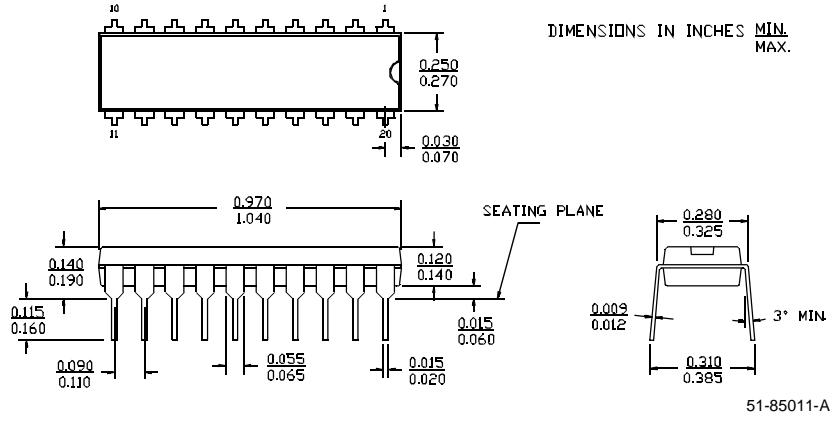
Parameter	Subgroups
<b>READ CYCLE</b>	
t <sub>RC</sub>	7, 8, 9, 10, 11
t <sub>AA</sub>	7, 8, 9, 10, 11
t <sub>OHA</sub>	7, 8, 9, 10, 11
t <sub>ACE</sub>	7, 8, 9, 10, 11
t <sub>RCS</sub>	7, 8, 9, 10, 11
t <sub>RCH</sub>	7, 8, 9, 10, 11
<b>WRITE CYCLE</b>	
t <sub>WC</sub>	7, 8, 9, 10, 11
t <sub>SCE</sub>	7, 8, 9, 10, 11
t <sub>AW</sub>	7, 8, 9, 10, 11
t <sub>HA</sub>	7, 8, 9, 10, 11
t <sub>SA</sub>	7, 8, 9, 10, 11
t <sub>PWE</sub>	7, 8, 9, 10, 11
t <sub>SD</sub>	7, 8, 9, 10, 11
t <sub>HD</sub>	7, 8, 9, 10, 11

## Package Diagrams

**20-Lead (300-Mil) CerDIP D6**  
MIL-STD-1835 D-8 Config. A



**20-Lead (300-Mil) Molded DIP P5**





## Package Diagrams (continued)

20-Lead (300-Mil) Molded SOJ V5

